

Atsushi Waseda

List of Publications by Year in descending order

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33
papers

950
citations

623734

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33
all docs

33
docs citations

33
times ranked

411
citing authors

#	ARTICLE	IF	CITATIONS
1	Uniformity evaluation of lattice spacing of silicon crystals for the realization of the kilogram. Measurement: Sensors, 2021, 18, 100204.	1.7	0
2	High-efficiency ultra-precision comparator for d -spacing mapping measurement of silicon. Journal of Synchrotron Radiation, 2020, 27, 577-582.	2.4	2
3	Absolute measurement of the density of silicon spheres to improve the primary density standard of NMJ. Metrologia, 2020, 57, 025006.	1.2	6
4	Improvement of the self-referenced lattice comparator: From using a pencil beam to a brush beam. AIP Conference Proceedings, 2019, , .	0.4	0
5	Uniformity Evaluation of Lattice Spacing of ^{28}Si Single Crystals. IEEE Transactions on Instrumentation and Measurement, 2017, 66, 1304-1308.	4.7	8
6	A new ^{28}Si single crystal: counting the atoms for the new kilogram definition. Metrologia, 2017, 54, 693-715.	1.2	92
7	Improved measurement results for the Avogadro constant using a ^{28}Si -enriched crystal. Metrologia, 2015, 52, 360-375.	1.2	143
8	Homogeneity Characterization of Lattice Spacing of Silicon Single Crystals. IEEE Transactions on Instrumentation and Measurement, 2015, 64, 1692-1695.	4.7	11
9	Counting the atoms in a ^{28}Si crystal for a new kilogram definition. Metrologia, 2011, 48, S1-S13.	1.2	160
10	Fast X-ray reflectivity measurement using a cooling PIN photodiode. IOP Conference Series: Materials Science and Engineering, 2011, 24, 012025.	0.6	0
11	Density Comparison of Isotopically Purified Silicon Single Crystals by the Pressure-of-Flotation Method. IEEE Transactions on Instrumentation and Measurement, 2011, 60, 2539-2543.	4.7	2
12	Determination of the Avogadro Constant by Counting the Atoms in a ^{28}Si Crystal. Physical Review Letters, 2011, 106, 030801.	7.8	183
13	Homogeneity characterization of lattice spacing of silicon single crystals by a self-referenced lattice comparator. Metrologia, 2011, 48, S55-S61.	1.2	25
14	Profile Measurement of Polished Surface with Respect to a Lattice Plane of a Silicon Crystal Using a Self-Referenced Lattice Comparator. International Journal of Automation Technology, 2011, 5, 179-184.	1.0	3
15	A Silicon d -spacing Mapping Measurement System With Resolution of 10^9 Å. , 2010, , .		2
16	Status of the international effort on the x-ray crystal density work and its progress towards a measurement of the Avogadro constant. , 2008, , .		0
17	Density measurement of a small ^{28}Si single crystal. , 2008, , .		0
18	Density Evaluation of Silicon Thermal-Oxide Layers on Silicon Crystals by the Pressure-of-Flotation Method. IEEE Transactions on Instrumentation and Measurement, 2007, 56, 628-631.	4.7	18

#	ARTICLE	IF	CITATIONS
19	Present State of the Avogadro Constant Determination From Silicon Crystals With Natural Isotopic Compositions. IEEE Transactions on Instrumentation and Measurement, 2005, 54, 854-859.	4.7	73
20	Density Measurement of a Thin-Film by the Pressure-of-Flotation Method. IEEE Transactions on Instrumentation and Measurement, 2005, 54, 882-885.	4.7	12
21	Comparison of Density Difference Measurements at PTB and NMJJ. IEEE Transactions on Instrumentation and Measurement, 2005, 54, 877-881.	4.7	4
22	Accurate density measurements of reference liquids by a magnetic suspension balance. Metrologia, 2004, 41, S84-S94.	1.2	35
23	Density comparison measurements of silicon crystals by a pressure-of-flotation method at NMJJ. Metrologia, 2004, 41, S62-S67.	1.2	36
24	Evaluation of the molar volume of silicon crystals for a determination of the avogadro constant. IEEE Transactions on Instrumentation and Measurement, 2003, 52, 646-651.	4.7	44
25	Density comparison measurement of silicon by pressure of flotation method. IEEE Transactions on Instrumentation and Measurement, 2001, 50, 604-607.	4.7	16
26	Density measurements of silicon crystals by hydrostatic weighing [for Avogadro constant determination]. IEEE Transactions on Instrumentation and Measurement, 2001, 50, 616-621.	4.7	14
27	Development of a silicon density standard and precision density measurements of solid materials by hydrostatic weighing. Measurement Science and Technology, 2001, 12, 2031-2038.	2.6	27
28	High precision density comparison measurement of silicon crystals by the pressure of flotation method. Measurement Science and Technology, 2001, 12, 2039-2045.	2.6	30
29	The electron - positron momentum density and Fermi surface in. Journal of Physics Condensed Matter, 1996, 8, 2413-2423.	1.8	1
30	Density measurements of silicon crystals by hydrostatic weighing. , 0, , .		1
31	Density comparison measurements of silicon crystals by pressure of flotation method. , 0, , .		0
32	Lattice spacing mapping in large silicon ingot using high resolution lattice comparator. , 0, , .		1
33	Evaluation of the molar volume of silicon crystals for a determination of the Avogadro constant. , 0, , .		1